

Notice of References CitedApplication/Control No.
10/030,191Applicant(s)/Patent Under
Reexamination
BAYER, ERICHExaminer
Edgardo San MartinArt Unit
2837

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0172386	11-2002	Bayer, Erich	381/330
	B	US-2,763,334	09-1956	Name not available	181/135
	C	US-6,094,492	07-2000	Boesen, Peter V.	181/135
	D	US-2003/0112992	06-2003	Rapps, Gary M.	381/330
	E	US-2002/0096391	07-2002	Smith et al.	181/135
	F	US-5,048,090	09-1991	Geers, Wolfgang	381/328
	G	US-D221,442	08-1971	Feingold, Abraham	D24/174
	H	US-3,041,856	07-1962	Neal, J.	181/129
	I	US-2,939,923	06-1960	Henderson, J.D.	381/330
	J	US-2,545,731	03-1951	French, G.W.	181/135
	K	US-1,668,910	05-1928	JOnes, W.C.	181/130
	L	US-1,614,987	01-1927	Langenbeck et al.	181/135
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2002058086 A	02-2002	Japan	WATANABE, YOSHITAKA	H04R 01/10
	O	DE 10111467 A1	01-2002	Germany	BAYER et al.	H04R 25/00
	P	JP 2001333484 A	11-2001	Japan	WATANABE, YOSHITAKA	H04R 01/10
	Q	DE 10050766 A1	05-2001	Germany	BAYER et al.	H04R 25/00
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.